


<b>Search Notes</b>  	<b>Application/Control No.</b>  10522502	<b>Applicant(s)/Patent Under Reexamination</b>  ERTLE ET AL.
	<b>Examiner</b>  ROBERT HUBER	<b>Art Unit</b>  2892

SEARCHED			
Class	Subclass	Date	Examiner
257	048, 499, 775	4/23/08	RH
438	460	5/31/09	RH

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor Search - EAST (USOCR, USPAT, USPGPUB) - see printout	4/23/08	RH
PLUS search - keywords: passive, active, layer, multilayer, dielectric, insulating, silicon, dioxide, nitride, copper, interconnect, vias, pattern, contact, lead, test, polyimide	4/23/08	RH
EAST search (USPAT, USPGPUB, USOCR, FPRS, EPO, JPO, DERWENT, IBM) - see printout	4/23/08	RH
Updated EAST search (USPAT, USPGPUB, USOCR, FPRS, EPO, JPO, DERWENT, IBM) - see printout	10/24/08	RH
Updated EAST search (USPAT, USPGPUB, USOCR, FPRS, EPO, JPO, DERWENT, IBM) - see printout	3/31/09	RH
Updated EAST search (USPAT, USPGPUB, USOCR, FPRS, EPO, JPO, DERWENT, IBM) - see printout	11/04/09	RH
Updated EAST search (USPAT, USPGPUB, USOCR, FPRS, EPO, JPO, DERWENT, IBM) - see printout	2/18/10	RH
Updated EAST search (USPAT, USPGPUB, USOCR, FPRS, EPO, JPO, DERWENT, IBM) - see printout	7/20/10	RH
Updated EAST search (USPAT, USPGPUB, USOCR, FPRS, EPO, JPO, DERWENT, IBM) - see printout	1/5/11	RH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--